

NOTES:

1. SUBSTRATE:
FUSED SILICA
2. SURFACE S2 TO BE PARALLEL TO S1 TO WITHIN < 10 ARCMIN
3. COATING (APPLY ACROSS COATING APERTURE)

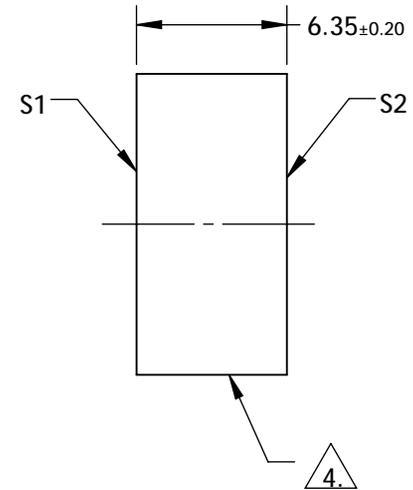
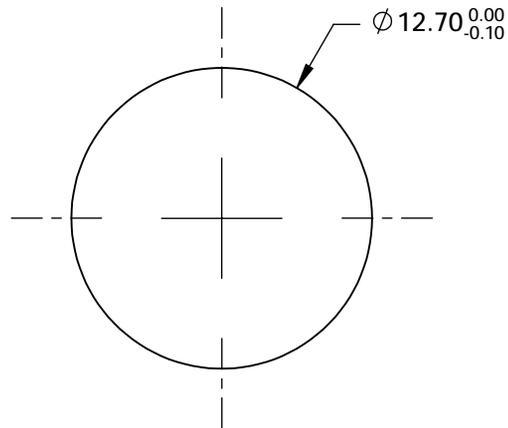
S1: R(AVG) > 99.8% @ 725 - 1000nm @ 45° AOI (P-POLARIZATION)
-70fs² @ 725 - 1000nm (P-POLARIZATION)

S2: NONE

DAMAGE THRESHOLD: 0.2 J/cm² @ 800nm, 50fs, 1kHz, 100µm BEAM DIAMETER

4. FINE GRIND SURFACE

5. ROHS COMPLIANT

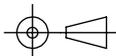


**FOR INFORMATION ONLY:
DO NOT MANUFACTURE
PARTS TO THIS DRAWING**

SPECIFICATIONS SUBJECT TO CHANGE WITHOUT NOTICE
DIMENSIONS ARE FOR REFERENCE ONLY

EO® Edmund Optics®

	S1	S2
SHAPE	PLANO	PLANO
IRREGULARITY (P-V) @632.8nm	λ/10	N/A
CLEAR APERTURE	Ø10.16	N/A
BEVEL	PROTECTIVE AS NEEDED	PROTECTIVE AS NEEDED

THIRD ANGLE PROJECTION 

ALL DIMS IN mm

TITLE	DWG NO	SHEET
Ø12.7mm Dia., 45°, 725 - 1000nm ULTRAFAST CHIRPED MIRROR	12420	1 OF 1